



PATENT

**In the United States Patent and Trademark Office**

Applicants: Linda BRALY et al. )  
Applicants' Reference: LAM2P298 )  
Application No. 10/002,676 )  
Filed: October 31, 2001 )  
Title: METHOD FOR PLANARIZATION ETCH )  
WITH IN-SITU MONITORING BY )  
INTERFEROMETRY PRIOR TO RECESS ETCH )

Examiner: Ahmed, Shamim  
Group Art Unit: 1765  
Date: February 2, 2007

**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, Virginia 22313-1450 on February 2, 2007.

Signed: Zulma Merida  
Zulma Merida

**Separate Letter to the Official Draftsperson**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Dear Sir:

Applicants hereby attach thirteen (13) sheets of formal drawings (Figures 1-13) for the above-referenced patent application. In the event the Draftsperson has any questions concerning the formal drawings, he or she is respectfully requested to contact the undersigned. If any fees are due in connection with the filing of these drawings, then please charge such fees to our Deposit Account No. 50-0805 (Order No. LAM2P298).

Respectfully submitted,  
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